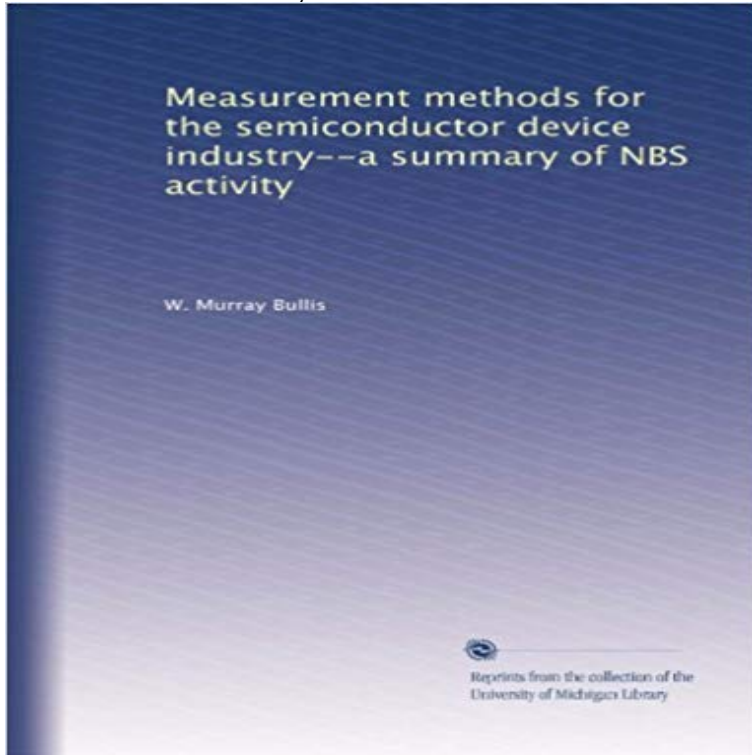


# Measurement methods for the semiconductor device industry--a summary of NBS activity



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